

Measurement Report for System Check (2450.000MHz)

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	50.0 x 10.0 x 8.0		Dipole 2.45G

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, HSL , Head Simulating Liquid		CW,	-0-	2450.000	7.25	1.866	40.251

Hardware Setup

Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 2081	H600~10000,0508	EX3DV4 - SN7693, 2024-11-20	DAE4 Sn1390, 2024-11-14

Scan Setup

	Area Scan	Zoom Scan	Measurement Results	Area Scan	Zoom Scan
Grid Extents [mm]	40.0 x 80.0	30.0 x 30.0 x 30.0	Date	2025-05-08	2025-05-08
Grid Steps [mm]	10.0 x 10.0	5.0 x 5.0 x 1.5	psSAR1g [W/kg]	12.5	12.4
Sensor Surface [mm]	3.0	1.4	psSAR10g [W/kg]	5.82	6.36
Graded Grid	N/A	Yes	Power Drift [dB]	-0.04	-0.11
Grading Ratio	N/A	1.5	Power Scaling	Disabled	Disabled
MAIA	N/A	N/A	Scaling Factor [dB]		
Surface Detection	VMS + 6p	VMS + 6p	TSL Correction	No correction	No correction
Scan Method	Measured	Measured	M2/M1 [%]		85.5
			Dist 3dB Peak [mm]		9.0

